

## **Thanks for attending IEEE AUTOTESTCON 2009!**

**Another IEEE AUTOTESTCON has been successfully completed - The 45<sup>th</sup> edition – and we must say Thanks to the exhibitors, the attendees, the Disneyland Hotel staff, and the organizing Committee, and everyone else that helped make this AUTOTESTCON a successful activity.**

To Attendees, we hope that you obtained the kind of advance technical information on automated test systems that you were seeking, and that your role in the field of ATE has been enhanced via your participation. We hope that you were able to visit the vendors in the exhibit halls and take advantage of the tremendous advancements in ATE and TPS technology that they offer to the community.

We also hope that you enjoyed the social activities that we provided to enhance your overall IEEE AUTOTESTCON experience at the Disneyland Resort & Conference Center.

An after-conference CD containing the presentations and a selection of conference photos is in preparation and will be mailed shortly to all registered attendees.

If you have any feedback for us for future consideration or enhancements of this Conference, please provide your feedback to AUTOTESTCON Board Executive Assistant, Judy Scharmann at [j.scharmann@ieee.org](mailto:j.scharmann@ieee.org).

To our Exhibitors, we hope that you also enjoyed the Conference and found the venue to be suitable for the furtherance of your business objectives. We would enjoy any feedback or suggestions that you have to offer for future AUTOTESTCONs. Please send comments to AUTOTESTCON Board Executive Assistant, Judy Scharmann at [j.scharmann@ieee.org](mailto:j.scharmann@ieee.org).

***The presentations given during the Plenary session*** are available at

[http://ieeaeess.org/main/index.php?option=com\\_docman&task=cat\\_view&gid=962&Itemid=108](http://ieeaeess.org/main/index.php?option=com_docman&task=cat_view&gid=962&Itemid=108).

***The Best Paper awards for this years AUTOTESTCON*** are as follows:

David M. Goodman Award for the outstanding Management Paper:

Mark Zachos, Dearborn Group, Inc., US  
*Vehicle Embedded Health Monitoring and Diagnostic System*

Walter E. Peterson Award for the best Technical Paper  
Anthony Estrada, BAE Systems, US  
*Proper Frequency Planning in a Synthetic Instrument RF System*

Best Undergraduate Student Paper  
Andrew Flanyak, Rowan University  
*Design-For-Testability On A Small Scale*

Best Graduate Student Paper  
Mikhail Itskovich, University of Maryland  
*Area Efficient Vector Multiplication for IDDT Test Calibration*

Best Graduate Student Paper Runner-up  
Anton Pirker-Fruhauf, University of Technics, Vienna, AT  
*A knowledge-based test program following the ATML Standard*

And the **Frank McGinnis Professional Achievement Award** in Automated Test went to  
Les Orledge, Textron/AAI Corp, Hunt Valley, MD

***We hope to see you at IEEE AUTOTESTCON 2010, Orlando Florida, September 13-17, Marriott Orlando World Center***

Bob Rassa, General Chair,  
IEEE AUTOTESTCON 2009